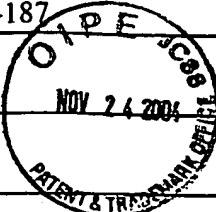


<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application		OFGS File No. <b>P/1878-187</b>			
		Applicant <b>Sei HIRADE</b>					
		Filing Date		Group Art Unit			
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate	
	US-						
	US-						
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<b>FOREIGN PATENT DOCUMENTS</b>							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
/EB/	11-191896	07-1999	Japan			Abstract	
/EB/	2000-068981	03-2000	Japan			Abstract	
/EB/	2001-094473	04-2001	Japan			Abstract	
/EB/	2001-189680	07-2001	Japan			Abstract	
/EB/	2002-009663	01-2002	Japan			Abstract	
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>							
Examiner <b>/Emmanuel Bayard/ (04/10/2007)</b>		Date Considered					
<small>EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.</small>							

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary)		Application 10/773,670		OFGS File No. P/1878-187	
		Applicant Sei HIRADE			
		Filing Date February 6, 2004		Group Art Unit 2661	



U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
/EB/	US-2002/0140603 A1	10-2002	Jeschke			
	US-					
	US-					
	US-					
	US-					
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	US-					
	US-					
	US-					
	US-					

FOREIGN PATENT DOCUMENTS							
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
/EB/		Search Report from European Patent Office issued September 20, 2004 in connection with
/EB/		corresponding application no. EP 04 25 0648

Examiner /Emmanuel Bayard/ (04/10/2007)	Date Considered
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